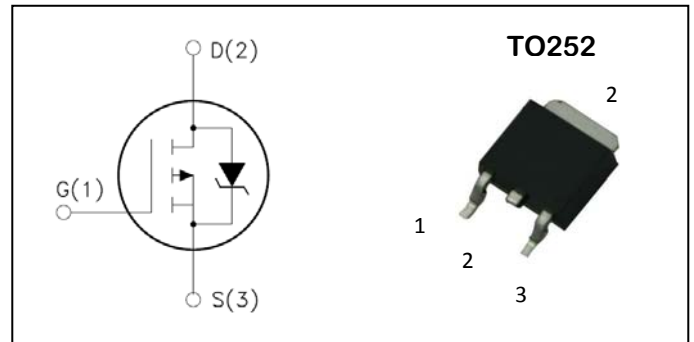


P-Channel Logic Level Enhancement Mode Field Effect Transistor

PRODUCT SUMMARY

V_{DSS}	I_D	$R_{DS(ON)}$ (m Ω)
-100V	-28A	76m Ω



Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Ratings	Unit	
Common Ratings				
V_{DSS}	Drain-Source Voltage	-100	V	
V_{GSS}	Gate-Source Voltage	± 20		
T_J	Maximum Junction Temperature	150	$^\circ\text{C}$	
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ\text{C}$	
I_S	Diode Continuous Forward Current	$T_C=25^\circ\text{C}$	-28	A
Mounted on Large Heat Sink				
I_{DM}	300 μs Pulse Drain Current Tested(1)	$T_C=25^\circ\text{C}$	-120	A
I_D	Continuous Drain Current	$T_C=25^\circ\text{C}$	-28	A
		$T_C=100^\circ\text{C}$	-16	A
P_D	Maximum Power Dissipation	$T_C=25^\circ\text{C}$	150	W
		$T_C=100^\circ\text{C}$	110	W

Thermal Characteristics

Symbol	Parameter	Ratings	Unit
R_{thJC}	Thermal resistance junction-case max	3	$^\circ\text{C/W}$
R_{thJA}	Thermal resistance junction-ambient max	50	$^\circ\text{C/W}$

1. Pulse width limited by maximum junction temperature.

Electrical Characteristics (TA=25°C Unless Otherwise Noted)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
On/off Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =-250uA	-100	--	--	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -100V, V _{GS} =0V	--	--	-25	uA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =-250uA	-1	--	-3	V
I _{GSS}	Gate Leakage Current	V _{GS} = ± 20V, V _{DS} =0V	--	--	± 100	nA
R _{DS(ON)}	Drain-Source On-state Resistance(2)	V _{GS} = -10V, I _{DS} =-15A	--	63	76	mΩ
		V _{GS} = -4.5V, I _{DS} =-8A	--	72	92	
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} = -25V, Frequency=1.0MHz	--	2550	--	pF
C _{oss}	Output Capacitance					
C _{rss}	Reverse Transfer Capacitance					
Switching Characteristics						
t _{d(ON)}	Turn-on Delay Time(1)	V _{DS} =-50V, I _D = -18A, V _{GS} = -10V, R _{GEN} =3.3 Ω	--	16	--	ns
t _r	Turn-on Rise Time(1)					
t _{d(OFF)}	Turn-off Delay Time(1)					
t _f	Turn-off Fall Time(1)					
Q _g	Total Gate Charge(1)	V _{DS} =-80V, V _{GS} = -10V, I _{DS} =-18A	--	78	--	nC
Q _{gs}	Gate-Source Charge(1)					
Q _{gd}	Gate-Drain Charge(1)					
Diode Characteristics						
V _{SD}	Diode Forward Voltage(2)	I _{SD} = -16A, V _{GS} = 0	--	--	-1.2	V
t _{rr}	Reverse Recovery Time	I _{SD} =-16A, dI _{SD} /dt=100A/μs	--	30	--	ns
q _{rr}	Reverse Recovery Charge		--	100	--	nC

NOTES:

1. Independent of operating temperature.
2. Pulse Test : Pulse width ≤ 300 μ s, Duty cycle ≤ 2%

Typical Performance Characteristics

Figure 1: On-Region Characteristics

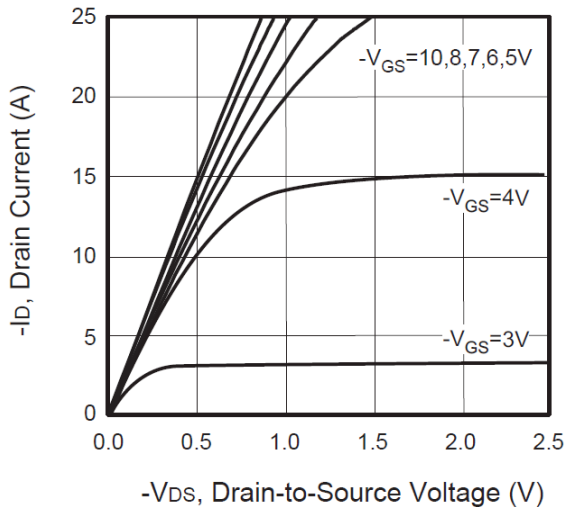


Figure 2: Gate Threshold Variation with Temperature

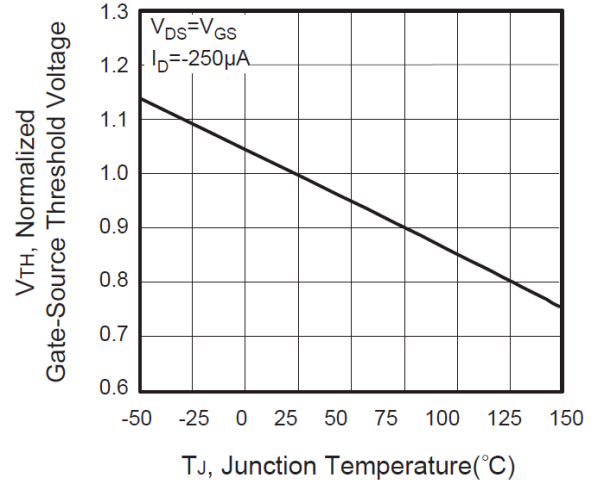


Figure 3: Transfer Characteristics

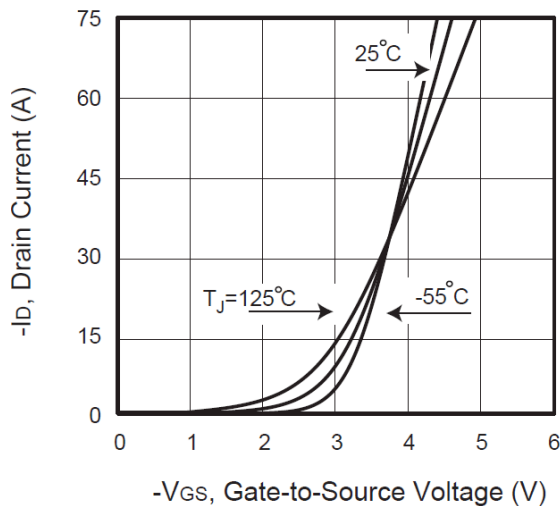


Figure 4: Maximum Safe Operating Area

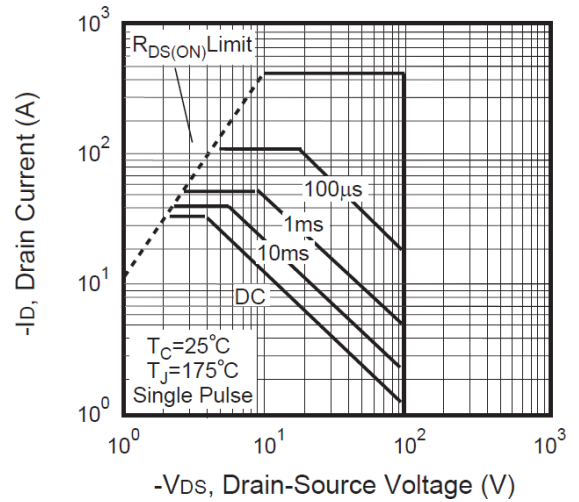


Figure 5: Capacitance Characteristics

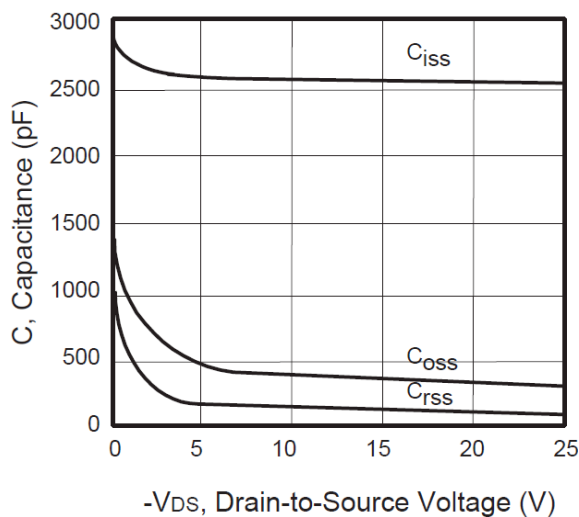


Figure 6: Gate Charge Characteristics

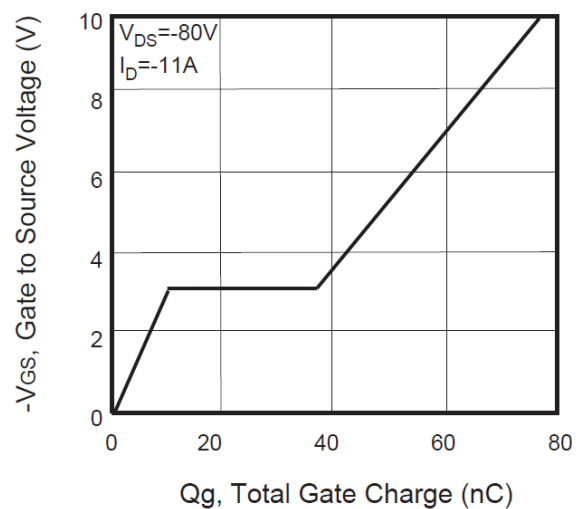


Figure 7: On-Resistance Variation vs. Temperature

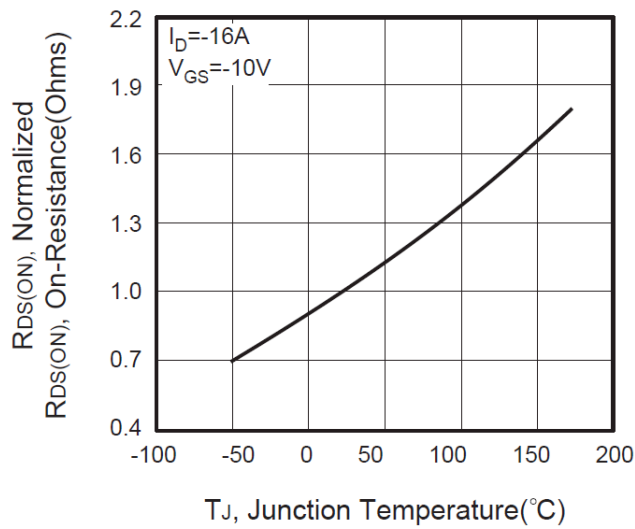


Figure 8: Body Diode Forward Voltage

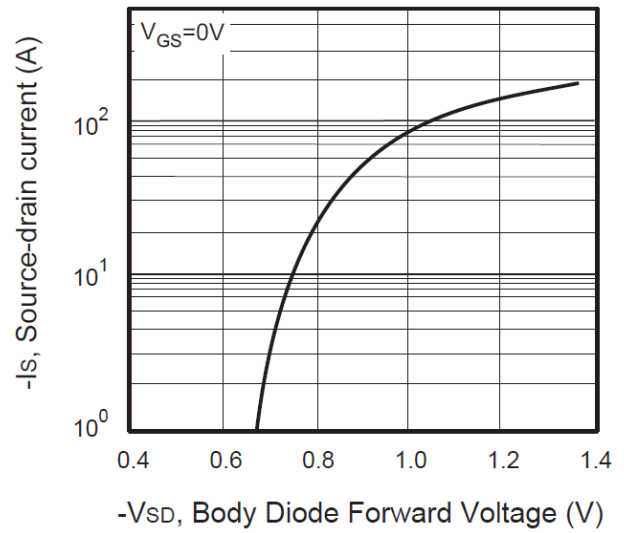
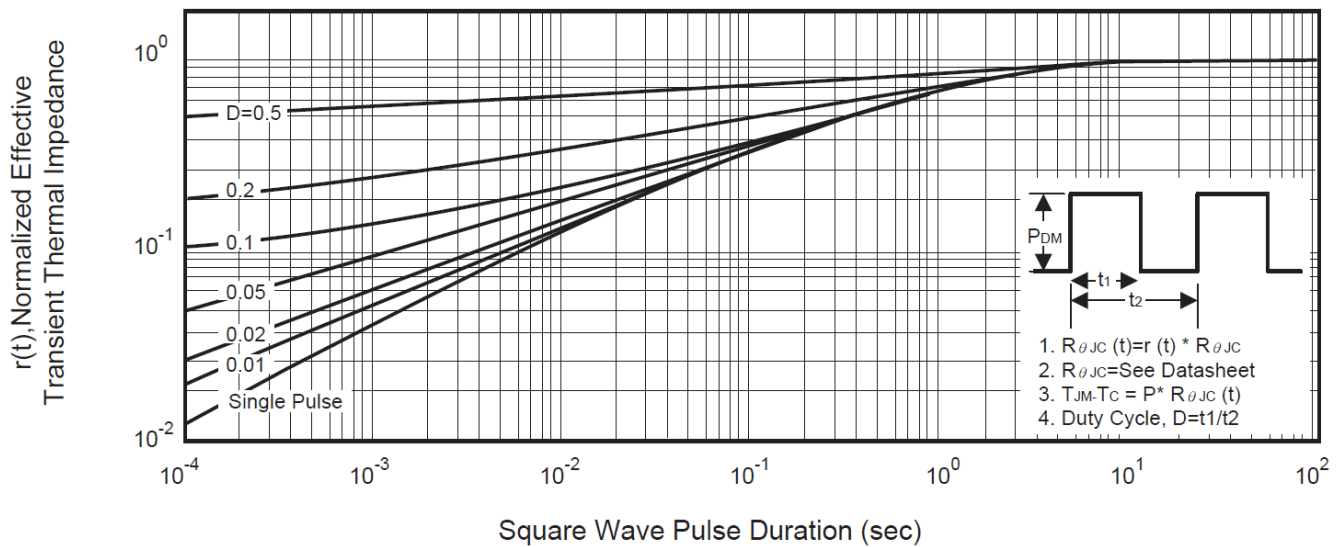
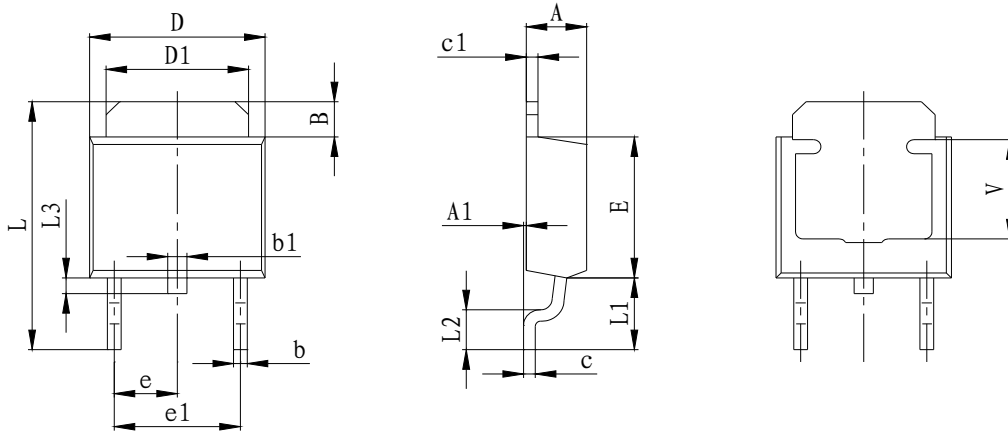


Figure 9. Transient Thermal Response Curve



PACKAGE MECHANICAL DATA
TO-252 Package Dimension



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
B	1.350	1.650	0.053	0.065
b	0.500	0.700	0.020	0.028
b1	0.700	0.900	0.028	0.035
c	0.430	0.580	0.017	0.023
c1	0.430	0.580	0.017	0.023
D	6.350	6.650	0.250	0.262
D1	5.200	5.400	0.205	0.213
E	5.400	5.700	0.213	0.224
e	2.300 TYP.		0.091 TYP.	
e1	4.500	4.700	0.177	0.185
L	9.500	9.900	0.374	0.390
L1	2.550	2.900	0.100	0.114
L2	1.400	1.780	0.055	0.070
L3	0.600	0.900	0.024	0.035
V	3.800 REF.		0.150 REF.	